Search Notes



Application/Control No.	Applicant(s)/Patent Under Reexamination	
	VONEMUDA ET AL	

 10553076
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 Examiner
 Art Unit

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SEARCHED					
Class	Subclass	Date	Examiner		
361	748,750,761,764,783				
257	787,E21.504,E23.004,E23.036,E23.066,E23.092				
174	250,251,258	6/2/08	ML		

SEARCH NOTES			
Search Notes	Date	Examiner	
EAST	6/1-2/08	ML	

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner

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